

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/774,690	TANAKA ET AL.	
Examiner		Art Unit		Page 1 of 1
Leith A. Al-Nazer		2821		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,954,320	09-1990	Birmingham et al.	422/186.04
	B	US-5,801,489	09-1998	Chism et al.	315/111.21
	C	US-6,455,014	09-2002	Hammerstrom et al.	422/186.04
	D	US-6,811,757	11-2004	Niv et al.	422/186.04
	E	US-6,818,193	11-2004	Christodoulatos et al.	423/210
	F	US-2001/0043890	11-2001	Son, Geon Seog	422/174
	G	US-2004/0050684	03-2004	Babko-Malyi et al.	204/164
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 08-155249	06-1996	Japan	Tetsuya et al.	B01D 53/32
	O	JP 09-000869	01-1997	Japan	Koichi et al.	B01D 53/56
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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